

40V

 $4.8 m\Omega$ 

 $5.9 m\Omega$ 

70A®

50A



### **Features**

- Advanced Process Technology
- Dual N-Channel MOSFET
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

Des	cri	pti	on

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast swithcing speed and improved repetitive avalanche rating. These features combine to make this product an extremely efficient and reliable device for use in Automotive and wide variety of other applications.

 $V_{\text{DSS}}$ 

R<sub>DS(on) typ.</sub>

ID (Silicon Limited)

In (Package Limited)



O	D	S
Gate	Drain	Source

# **Applications**

- 12V Automotive Systems
- · Brushed DC Motor
- Braking
- Transmission

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRFN8459	Dual PQFN 5mm x 6mm	Tape and Reel	4000	AUIRFN8459TR

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C (Bottom)</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ®	70	
I <sub>D</sub> @ T <sub>C (Bottom)</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	50	^
I <sub>D</sub> @ T <sub>C (Bottom)</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	50	Α
I <sub>DM</sub>	Pulsed Drain Current ①	320	
P <sub>D</sub> @T <sub>C (Bottom)</sub> = 25°C	Power Dissipation	50	W
	Linear Derating Factor	0.33	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②	66	mJ
E <sub>AS</sub> (Tested)	Single Pulse Avalanche Energy ®	110	
I <sub>AR</sub>	Avalanche Current ①	See Fig. 14, 15, 22a, 22b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①		
TJ	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		C

HEXFET® is a registered trademark of International Rectifier.

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/



### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
R <sub>θJC</sub> (Bottom)	Junction-to-Case ®		3.0	
R <sub>θ</sub> JC (Top)	Junction-to-Case ®		45	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑦		40	

# Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.037		V/°C	Reference to 25°C, I <sub>D</sub> = 1.0mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		4.8	5.9	mΩ	$V_{GS} = 10V, I_D = 40A $ ④
$V_{GS(th)}$	Gate Threshold Voltage	2.2	3.0	3.9	V	$V_{DS} = V_{GS}$ , $I_D = 50\mu A$
gfs	Forward Transconductance	66			S	$V_{DS} = 10V, I_{D} = 40A$
$R_G$	Internal Gate Resistance		1.9		Ω	
	Drain to Course Leekens Current			1.0		$V_{DS} = 40V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			150	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	n 1	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$\overline{Q_g}$	Total Gate Charge		40	60		I <sub>D</sub> = 40A
$\overline{Q_gs}$	Gate-to-Source Charge		13		0	V <sub>DS</sub> = 20V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		14		nC	V <sub>GS</sub> = 10V
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		26			$I_D = 40A, V_{DS} = 0V, V_{GS} = 10V$
t <sub>d(on)</sub>	Turn-On Delay Time		10			V <sub>DD</sub> = 26V
t <sub>r</sub>	Rise Time		55			I <sub>D</sub> = 40A
$t_{d(off)}$	Turn-Off Delay Time		25		ns	$R_G = 2.7\Omega$
t <sub>f</sub>	Fall Time		42			$V_{GS} = 10V$
C <sub>iss</sub>	Input Capacitance		2250			$V_{GS} = 0V$
Coss	Output Capacitance		340			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		215		pF	f = 1.0  MHz
Coss eff. (ER)	Effective Output Capacitance (Energy Related)		400			V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 32V ⑥
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)		490			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V $

### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			70⑥	^	MOSFET symbol
I <sub>S</sub>	(Body Diode)				Α	showing the
	Pulsed Source Current			320	^	integral reverse
I <sub>SM</sub>	(Body Diode) ②				Α	p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 40A$ , $V_{GS} = 0V$ ④
dv/dt	Peak Diode Recovery ③		7.0		V/ns	$T_J = 175$ °C, $I_S = 40$ A, $V_{DS} = 40$ V
1	Deverse Desevery Time		22			$T_{J} = 25^{\circ}C$
t <sub>rr</sub>	Reverse Recovery Time		23		ns	$T_J = 125^{\circ}C$ $V_R = 34V$ , $V_R = 40A$
	Dayoraa Dagayary Chargo		17		nC	$T_J = 25^{\circ}C$ di/dt = 100A/µs4
$Q_{rr}$	Reverse Recovery Charge		17		IIC	T <sub>J</sub> = 125°C
I <sub>RRM</sub>	Reverse Recovery Current		1.0		Α	T <sub>J</sub> = 25°C



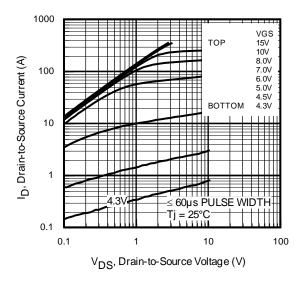


Fig. 1 Typical Output Characteristics

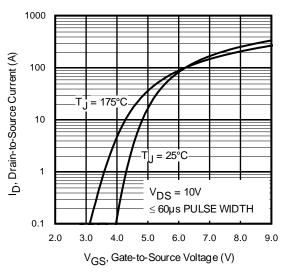


Fig. 3 Typical Transfer Characteristics

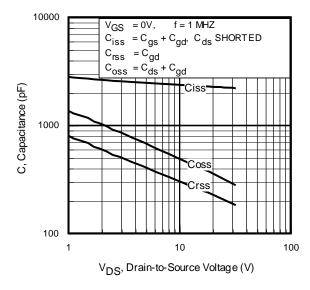


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

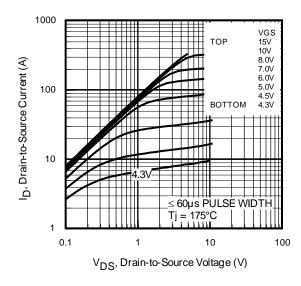


Fig. 2 Typical Output Characteristics

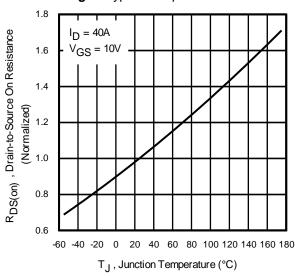


Fig. 4 Normalized On-Resistance vs. Temperature

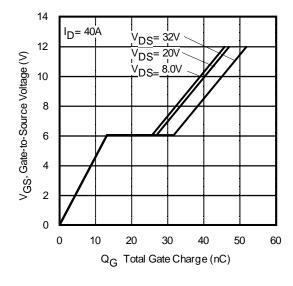


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



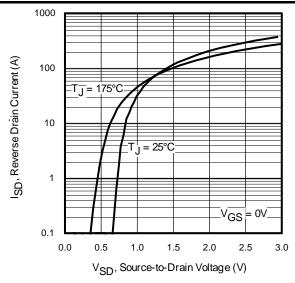


Fig. 7 Typical Source-to-Drain Diode

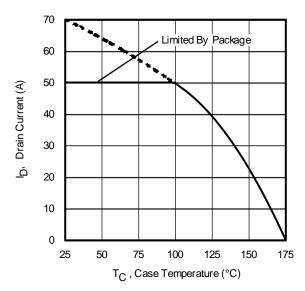


Fig 9. Maximum Drain Current vs. Case Temperature

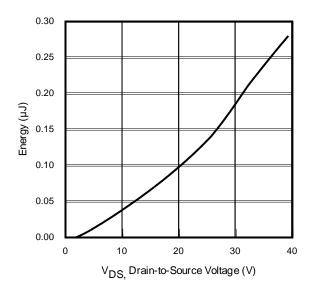


Fig 11. Typical Coss Stored Energy

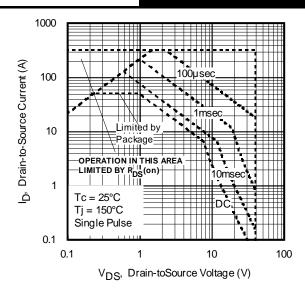


Fig 8. Maximum Safe Operating Area

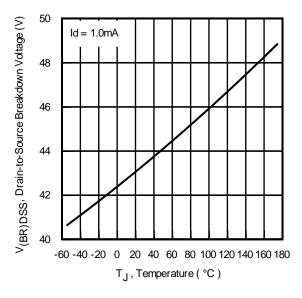


Fig 10. Drain-to-Source Breakdown Voltage

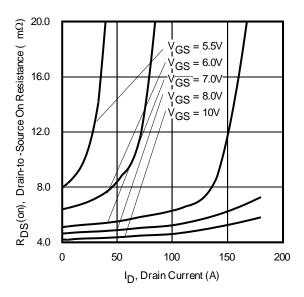


Fig 12. Typical On-Resistance vs. Drain Current



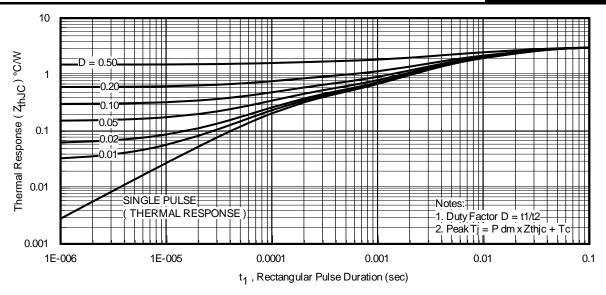


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

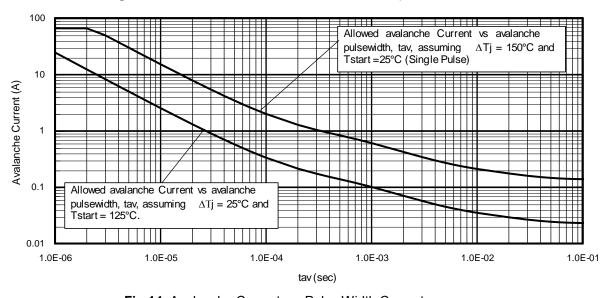


Fig 14. Avalanche Current vs. Pulse Width Current

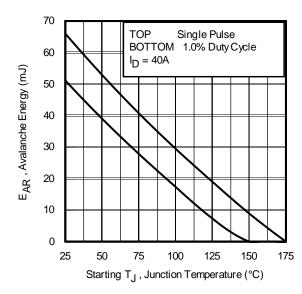


Fig 15. Maximum Avalanche Energy vs. Temperature

# Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.

- 2. Safe operation in Avalanche is allowed as long  $asT_{\text{jmax}}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4.  $P_{D (ave)}$  = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- ΔT = Allowable rise in junction temperature, not to exceed T<sub>jmax</sub> (assumed as 25°C in Figure 14, 15).

 $t_{av}$  = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

PD (ave) = 1/2 (  $1.3 \cdot BV \cdot I_{av}$ ) =  $\Delta T / Z_{thJC}$ 

 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$ 

 $E_{AS (AR)} = P_{D (ave)} t_{av}$ 



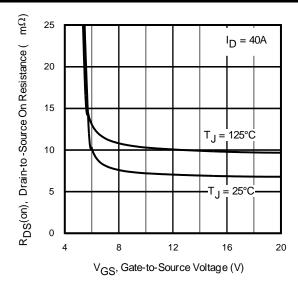


Fig 16. Typical On-Resistance vs. Gate Voltage

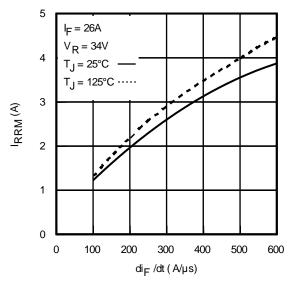


Fig 18. Typical Recovery Current vs. dif/dt

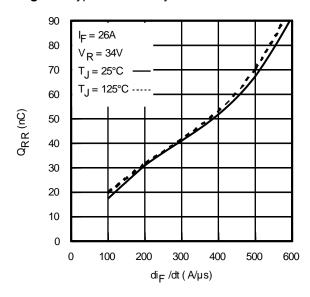


Fig 20. Typical Recovery Current vs. dif/dt

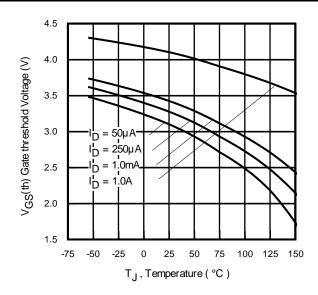


Fig 17. Threshold Voltage vs. Temperature

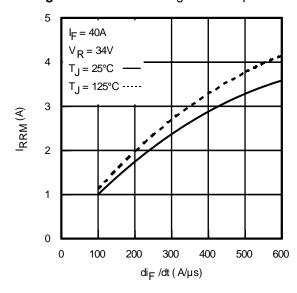


Fig 19. Typical Stored Charge vs. dif/dt

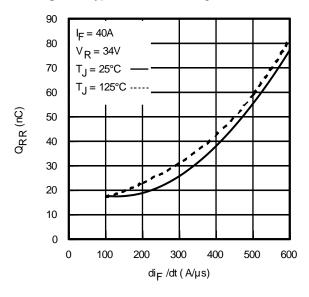
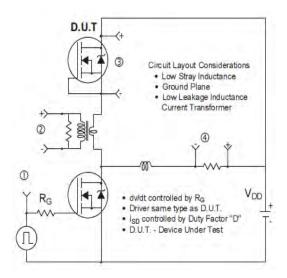


Fig 21. Typical Stored Charge vs. dif/dt





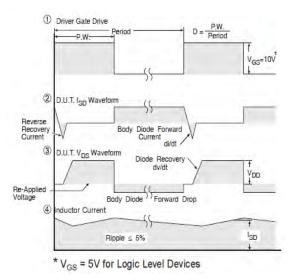


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

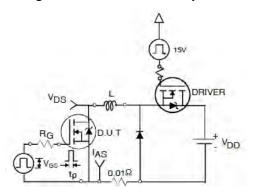


Fig 22a. Unclamped Inductive Test Circuit

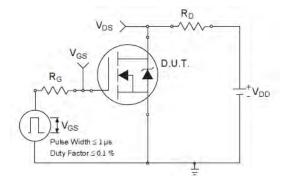


Fig 23a. Switching Time Test Circuit

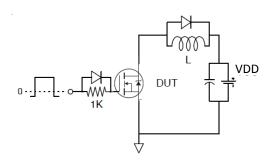


Fig 24a. Gate Charge Test Circuit

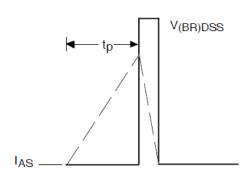


Fig 22b. Unclamped Inductive Waveforms

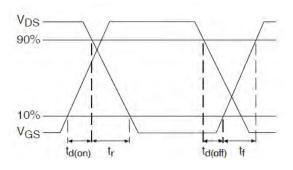


Fig 23b. Switching Time Waveforms

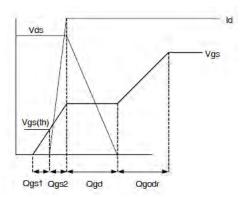
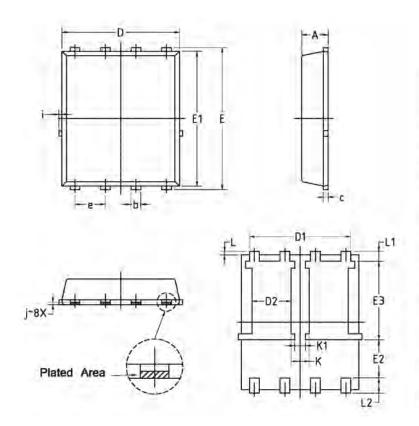


Fig 24b. Gate Charge Waveform



# **Dual PQFN 5x6 Package Details**



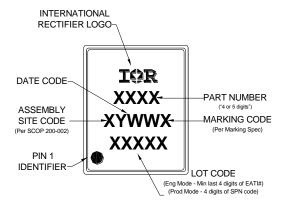
S.		COM	MON			
M B O		IM	INCH			
0	MIN.	MAX.	MIN.	MAX.		
Α	1.00	1.20	0.039	0.047		
b	0.30	0,50	0.012	0.020		
C	0.203	BSC	0.008	BSC		
D	4.80	5.00	0.189	0.197		
D1	4.06	4.36	0.160	0.172		
D2	1.47	1.77	0.058	0.070		
E	5.90	6.20	0.232	0.244		
E1	5.65	5.85	0.222	0.230		
E2	1.45		0.057	1735		
E3	3.20	3.50	0.126	0.138		
e	1.27	BSC	0.05 B	ISC		
L	0.05	0.25	0.002	0.010		
L1	0.325	0.525	0.013	0.021		
L2	0.500	0.800	0.020	0.031		
ï.		0.20		0.008		
K	0.61	0.91	0.024	0.036		
K1	0.31	0.60	0.012	0.024		
j	0.101	BSC	0.00	4BSC		

For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: http://www.irf.com/technical-info/appnotes/an-1136.pdf

For more information on package inspection techniques, please refer to application note AN-1154:

http://www.irf.com/technical-info/appnotes/an-1154.pdf

# **Dual PQFN 5x6 Part Marking**



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



# Qualification Information<sup>†</sup>

<u> Quannoution</u>	i iiiioiiiiatioii				
		Automotive (per AEC-Q101)			
Qualification Level  Comments: This part number(s) passed Automotive qualification. dustrial and Consumer qualification level is granted by extension of er Automotive level.					
Moisture Sensit	tivity Level	Dual PQFN 5mm x 6mm MSL1			
	Human Body Model	Class H1B(+/- 1000V) <sup>††</sup>			
			AEC-Q101-001		
ESD	Charged Device Model	Class C5 (+/- 1000V) <sup>††</sup>			
		AEC-Q101-005			
RoHS Complia	int	Yes			

- † Qualification standards can be found at International Rectifier's web site: <a href="http://www.irf.com/">http://www.irf.com/</a>
- †† Highest passing voltage.

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L =75 $\mu$ H,  $R_G = 50\Omega$ ,  $I_{AS} = 40A$ ,  $V_{GS} = 10V$ .
- $\exists \quad I_{SD} \leq 50 A, \ di/dt \leq 650 A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175 ^{\circ}C.$
- 4 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- $\odot$  C<sub>oss eff. (TR)</sub> is a fixed capacitance that gives the same charging time as Coss while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- ©  $C_{oss\ eff.\ (ER)}$  is a fixed capacitance that gives the same energy as Coss while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994: <a href="http://www.irf.com/technical-info/appnotes/an-994.pdf">http://www.irf.com/technical-info/appnotes/an-994.pdf</a>
- $\otimes$  R<sub> $\theta$ </sub> is measured at T<sub>J</sub> of approximately 90°C.
- $\odot$  This value determined from sample failure population, starting T<sub>J</sub> = 25°C, L= 75μH, R<sub>G</sub> = 50Ω, I<sub>AS</sub> = 40A, V<sub>GS</sub> =10V.
- © Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 50A.
  Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements



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IR products are neither designed nor intended for use in automotive applications or environments unless the specific IR products are designated by IR as compliant with ISO/TS 16949 requirements and bear a part number including the designation "AU". Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, IR will not be responsible for any failure to meet such requirements.

For technical support, please contact IR's Technical Assistance Center

http://www.irf.com/technical-info/

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